Challenges and Solutions in Modern Circuit Placement

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Sponsors: IBM, Intel, ITRI, NSC, MediaTek, RealTek, SpringSoft







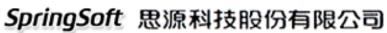




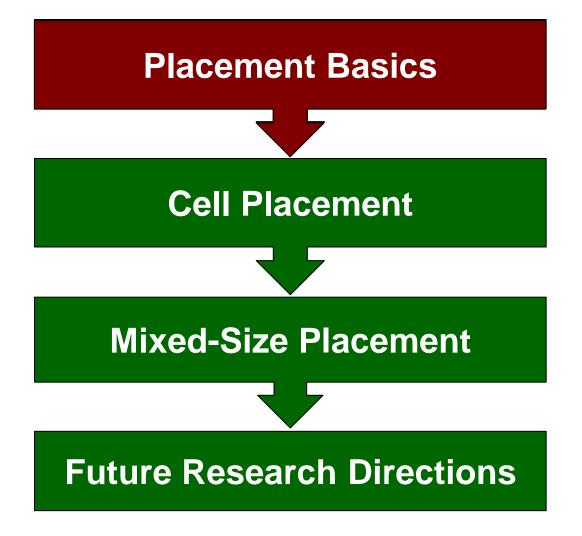




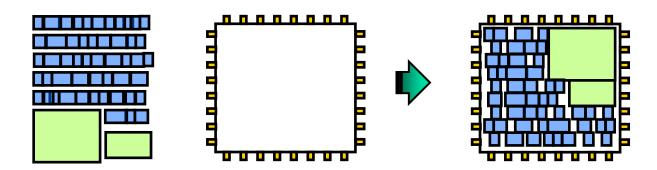




Outline

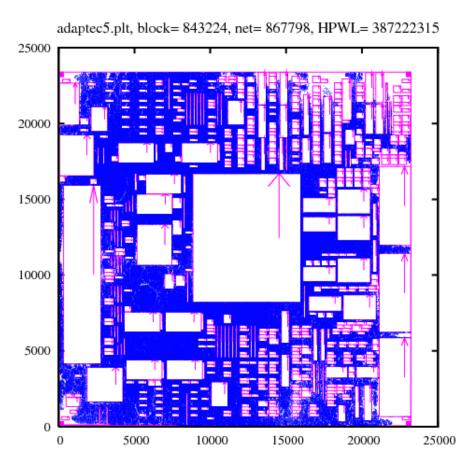


VLSI Placement

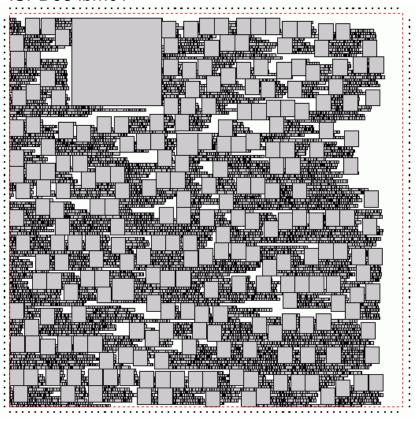


- Placement: Place objects into a fixed die s.t. no objects overlap with each other & some cost metric (e.g., wirelength) is optimized
- Attract much attention due to fast growth in design complexity and many others
 - EETimes (4/10/2003): far away from the optimal wirelength
 - Is still far away from optimal??
- More than 20 new academic placers since 2000
- ACM ISPD Placement Contests in 2005, 2006, and 2011

Example Placements



ISPD98 ibm01



842K movable cells 646 fixed macros 868K nets

12,752 cells, 247 macros Amax/Amin = 8416

Wires are not shown here!!

Modern Placement Challenges

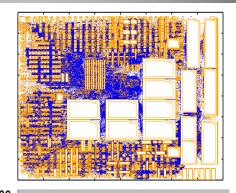
- High complexity
 - Millions of objects to be placed
- Placement constraints
 - Preplaced blocks
 - Chip density, etc.

• Mixed-size placement

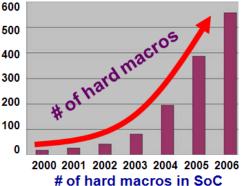
Hundreds/Thousands
 of large macros with
 millions of small
 standard cells

3D IC design

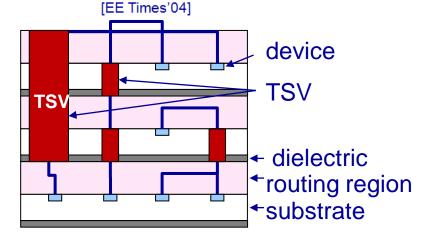
 Through-the-silicon via (TSV) induced multi-tier placement



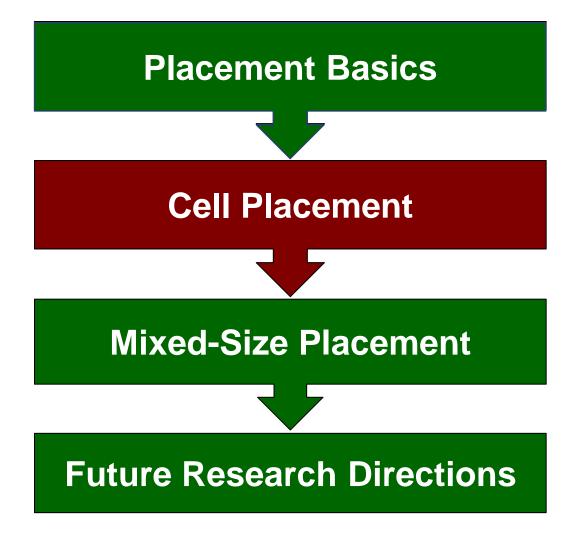
2.5M placeable objects mixed-size design



Macros have revolutionized SoC design

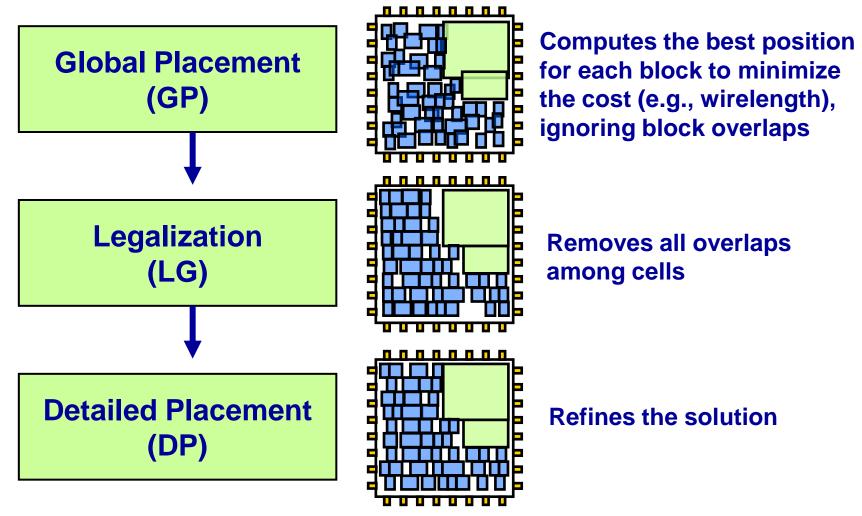


Outline



NTUplace3 Placement Flow

 Chen, et al., "A high quality analytical placer considering preplaced blocks and density constraint," ICCAD-06 (TCAD-08)

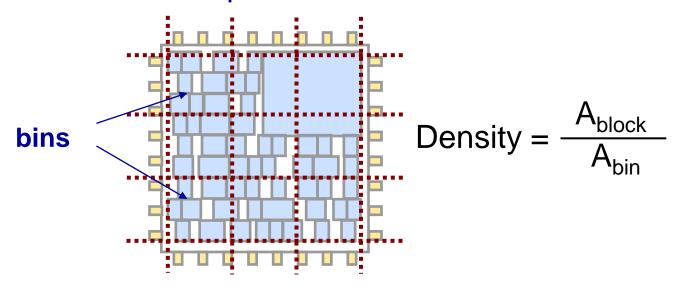


Placement with Density Constraint

- Given the chip region and block dimensions, divide the placement region into bins
- Determine (x, y) for all movable blocks

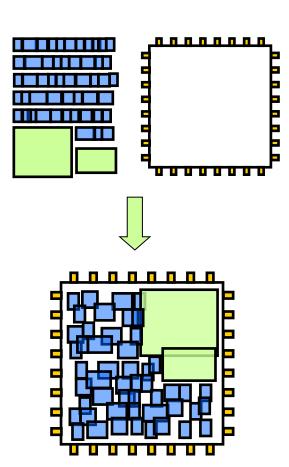
min W(x, y) // wirelength function

- s.t. 1. Density_b(x, y) \leq MaximumDensity_b for each bin b
 - 2. No overlap between blocks



Global Placement

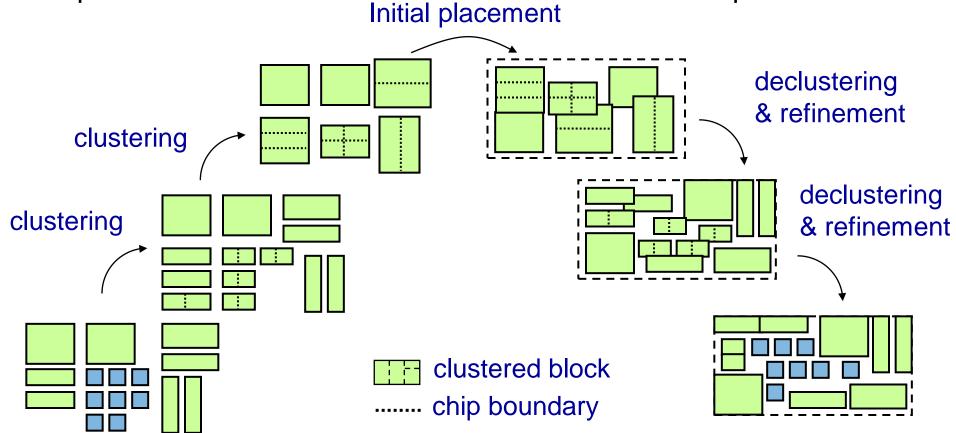
- Placement flow
 - Global placement
 - Multilevel framework
 - Analytical formulation with a nonlinear objective function
 - Smoothing techniques for preplaced blocks
 - Free-space allocation for density control
 - Legalization
 - Detailed placement



Multilevel Global Placement

Cluster the blocks based on connectivity/area to reduce the problem size.

Iteratively decluster the clusters and further refine the placement



Analytical Placement Model

- Analytical placement during declustering
- Global placement problem (allow overlaps)

min
$$W(x, y)$$

s.t. $D_b(x, y) \le M_b$

Minimize HPWL (wirelength)

D_b: density for bin b

M_b: max density for bin b

Relax the constraints into the objective function

min W(x, y) +
$$\lambda \Sigma(D_b(x, y) - M_b)^2$$

- Use the gradient method to solve it
- Increase λ gradually to find the optimal (x, y) under density constraint

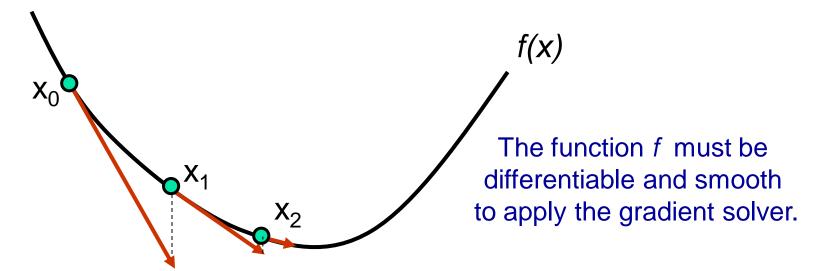
Gradient Solver

min f(x)

[Gradient Solver]

x₀ ← initial value Repeat until convergence

$$x_{i+1} = x_i - f'(x)|_{x=xi}$$
 * stepsize

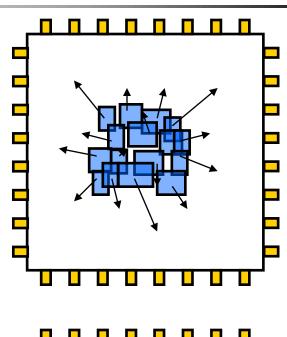


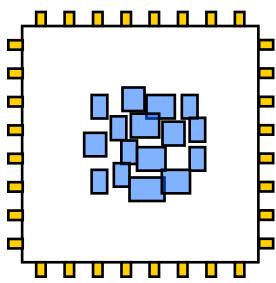
Dynamic Step-Size Control

- Step size is too large
 - → May not converge to a good solution
- Step size is too small
 - → Incur long running time
- Adjust the step size s.t. the average Euclidean movement of all blocks is a fixed value

step size
$$\alpha_k = \frac{s}{\|\mathbf{d}_k\|_2}$$

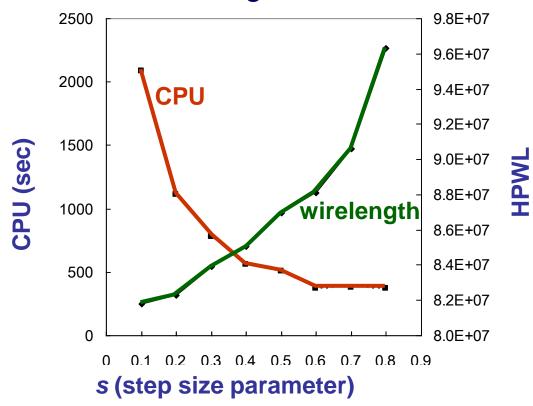
- \mathbf{d}_k conjugate directions
- s a user-specified value
 - $\sim 0.2 * bin width$





Effects of the Step-Size Parameter

- Small step size
 - Larger runtime, smaller HPWL (wirelength)
- Large step size
 - Smaller runtime, larger HPWL

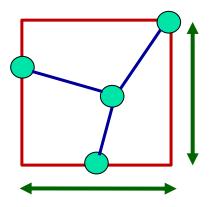


HPWL Wirelength Model

Ideal: Half-perimeter wirelength (HPWL) model

$$W(\mathbf{x}, \mathbf{y}) = \sum_{e \in E} (\max_{v_i, v_j \in e} |x_i - x_j| + \max_{v_i, v_j \in e} |y_i - y_j|)$$

- Is not smooth and differentiable
- Approximations: quadratic, L_p-norm, log-sum-exp,
 CHKS wirelength models, etc.



Log-sum-exp (LSE) Wirelength Model

Log-sum-exp (LSE) wirelength model [Naylor et al., 2001]

$$W_{LSE}(\mathbf{x}, \mathbf{y}) = \gamma \sum_{e \in E} \left(\ln \sum_{v_k \in e} \exp(x_k / \gamma) + \ln \sum_{v_k \in e} \exp(-x_k / \gamma) + \ln \sum_{v_k \in e} \exp(y_k / \gamma) + \ln \sum_{v_k \in e} \exp(-y_k / \gamma) \right)$$

$$\max\{\mathbf{x}\} = -\min\{-\mathbf{x}\}; \quad \max\{\mathbf{x}\} \cong \gamma \ln \sum_{v_k \in e} \exp(x_k / \gamma)$$

- Is an effective smooth & differentiable approximation for HPWL
- − Approaches exact HPWL when $\gamma \rightarrow 0$
- Has dominated modern placement for 10+ years!

Can we do better??

Our Weighted-Average (WA) Model

$$W_{WA}(\mathbf{x}, \mathbf{y}) = \sum_{e \in E} \left(\frac{\sum_{v_i \in e} x_i \exp(x_i / \gamma)}{\sum_{v_i \in e} \exp(x_i / \gamma)} - \frac{\sum_{v_i \in e} x_i \exp(-x_i / \gamma)}{\sum_{v_i \in e} \exp(-x_i / \gamma)} + \frac{\sum_{v_i \in e} y_i \exp(y_i / \gamma)}{\sum_{v_i \in e} \exp(y_i / \gamma)} - \frac{\sum_{v_i \in e} y_i \exp(-y_i / \gamma)}{\sum_{v_i \in e} \exp(-y_i / \gamma)} \right)$$

- 1st model that outperforms LSE theoretically & empirically [Hsu, Chang, Balabanov, DAC-11]
- Weighted average of a set of x coordinates, \mathbf{x}_e , of a net e:
 - $X(\mathbf{x}_e)$ can approximate the maximum value of \mathbf{x}_e by setting the weight function of x_i : $F(x_i) = \exp(x_i/\gamma)$, a fast growing function

$$X(\mathbf{x}_e) = \frac{\sum_{v_i \in e} x_i F(x_i)}{\sum_{v_i \in e} F(x_i)} \quad \underset{max}{\longrightarrow} \quad X_{max}(\mathbf{x}_e) = \frac{\sum_{v_i \in e} x_i \exp(x_i / \gamma)}{\sum_{v_i \in e} \exp(x_i / \gamma)}$$

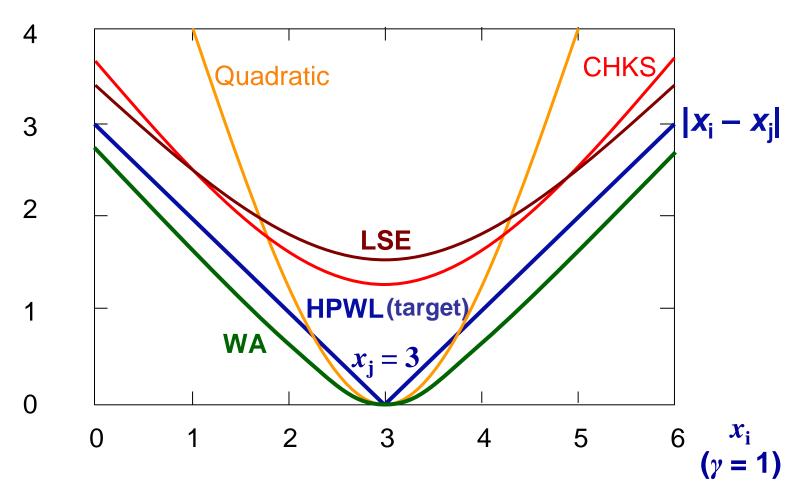
- Is an effective smooth, differentiable, quasiconvex function for HPWL approximation
- Approaches exact HPWL when $\gamma \rightarrow 0$

Popular Wirelength Models

$$\begin{aligned} \text{HPWL} \qquad W(\mathbf{x},\mathbf{y}) &= \sum_{\text{net } e} \left(\max_{v_i,v_j \in e} |x_i - x_j| + \max_{v_i,v_j \in e} |y_i - y_j| \right) \\ \text{quadratic} \qquad & \frac{1}{2} \sum_{i=1}^n \sum_{j=1}^n \gamma_{ij} [(x_i - x_j)^2 + (y_i - y_j)^2] \\ \text{Log-sum-exp} \qquad & \gamma \sum_{e \in E} (\log \sum_{v_k \in e} \exp(x_k/\gamma) + \log \sum_{v_k \in e} \exp(-x_k/\gamma) + \log \sum_{v_k \in e} \exp(-y_k/\gamma) \right) \\ \text{Lg-norm} \qquad & \sum_{e \in E} ((\sum_{v_k \in e} x_k^p)^{\frac{1}{p}} - (\sum_{v_k \in e} x_k^{-p})^{-\frac{1}{p}} + (\sum_{v_k \in e} y_k^p)^{\frac{1}{p}} - (\sum_{v_k \in e} y_k^{-p})^{-\frac{1}{p}}) \\ \text{CHKS} \qquad & CHKS(x_1, x_2) = \frac{\sqrt{(x_1 - x_2)^2 + t^2} + x_1 + x_2}{2}, \\ \text{Weighted-average} \qquad & \sum_{e \in E} \left(\frac{\sum_{v_i \in e} x_i \exp(x_i/\gamma)}{\sum_{v_i \in e} \exp(x_i/\gamma)} - \frac{\sum_{v_i \in e} x_i \exp(-x_i/\gamma)}{\sum_{v_i \in e} \exp(-x_i/\gamma)} + \frac{\sum_{v_i \in e} y_i \exp(y_i/\gamma)}{\sum_{v_i \in e} \exp(y_i/\gamma)} - \frac{\sum_{v_i \in e} y_i \exp(-y_i/\gamma)}{\sum_{v_i \in e} \exp(-y_i/\gamma)} \right). \end{aligned}$$

Popular Wirelength Model Comparisons

wirelength Quasi/convex functions with 2 variables



Theoretical Comparisons

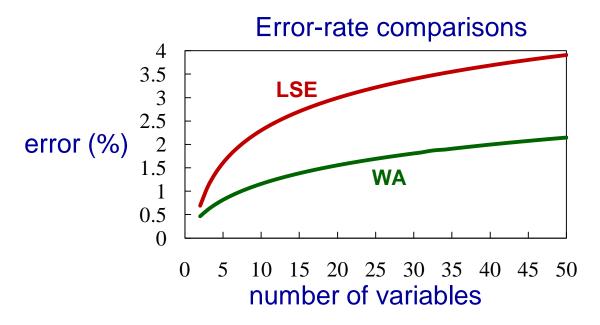
Theorem: The estimation error bound of the WA model is

$$0 \le \varepsilon_{WA}(\mathbf{x}_e) \le \frac{\gamma(x_{\text{max}} - x_{\text{min}})}{1 + e^{(x_{\text{max}} - x_{\text{min}})} / n}.$$

 $\mathbf{x}_e = \{x_i | v_i \in e\}$: a set \mathbf{x} of coordinates associated with net e

• Theorem: The error upper bound of the WA model is smaller than that of the LSE model:

$$\varepsilon_{WA}(\mathbf{x}_e) \le \varepsilon_{LSE}(\mathbf{x}_e) = \gamma \ln n$$



Wirelength Model Comparison

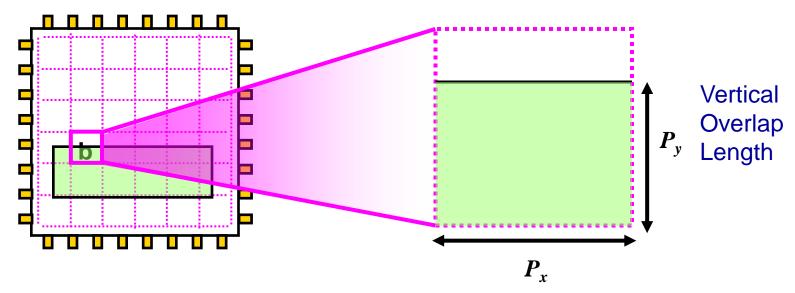
- Integrated both the LSE and WA models into NTUplace3 [ICCAD-06], a leading academic placer
- Used ISPD-06 placement benchmark circuits
 #Cells: 330K—2481K, #Nets: 338K—2636K
- The WA model can achieve averagely 2% shorter total wirelength than the LSE model

Wirelength Model	Wirelength	CPU Time
LSE	1.000	1.000
WA	0.980	1.066

The results show that WA outperforms LSE consistently

Density Model

 Compute the block area in each bin to obtain the bin density



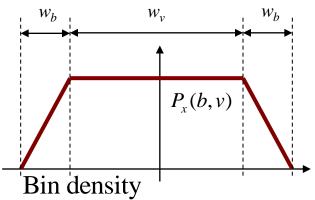
Horizontal Overlap Length

Bin density

$$D_b(\mathbf{x}, \mathbf{y}) = \sum_{\mathbf{y} \in \mathbf{V}} P_{\mathbf{x}}(b, \mathbf{y}) P_{\mathbf{y}}(b, \mathbf{y})$$

Density Smoothing

 Apply the bell-shaped function to make bin density function smooth [Kahng & Wang, ICCAD-04]



Bell-shaped smoothing function Continuous &

differentiable Bin density

Overlap length $D_b(\mathbf{x}, \mathbf{y}) = \sum_{\mathbf{v} \in \mathbf{V}} P_{\mathbf{x}}(b, \mathbf{v}) P_{\mathbf{y}}(b, \mathbf{v})$ function

$$D_b'(\mathbf{x}, \mathbf{y}) = \sum_{\mathbf{v} \in \mathbf{V}} c_{\mathbf{v}} p_{\mathbf{x}}(b, \mathbf{v}) p_{\mathbf{y}}(b, \mathbf{v})$$

 $p_x(b,v)$

$$\begin{cases} p_x(b,v) = \\ 1 - ad_x^2, & 0 \le d_x \le w_v/2 + w_b \\ b(d_x - 2w_b - 2w_g)^2, & w_v/2 + w_b \le d_x \le w_v/2 + 2w_b \\ 0, & w_v/2 + 2w_b \le d_x, \end{cases}$$

where

$$a = 4/((w_v + 2w_b)(w_v + 4w_b))$$

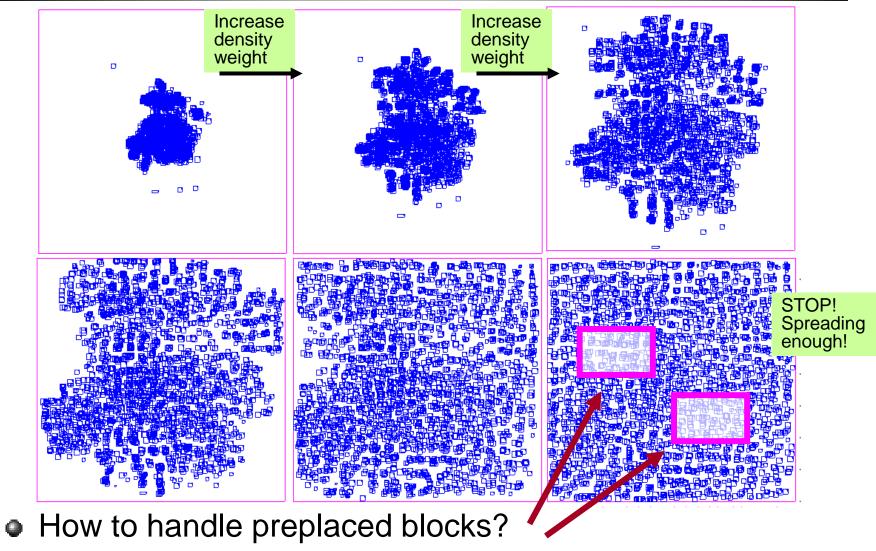
$$b = 2/(w_b(w_v + 4w_b)),$$

$$w_b \quad \text{bin width}$$

$$w_v \quad \text{block width}$$

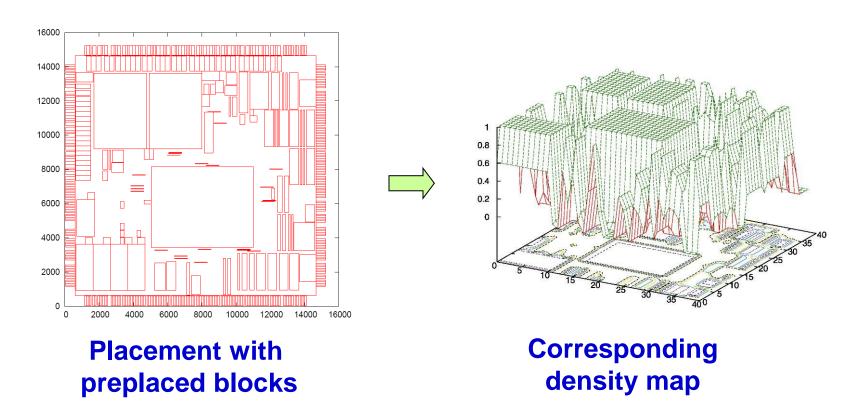
$$c_v \quad \text{normalization factor}$$

Placement Process



Pre-defined density makes cell spreading harder.

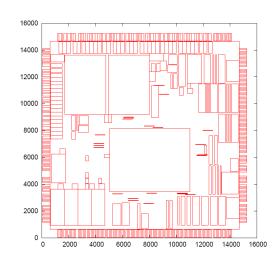
Density Map with Preplaced Blocks



Two major problems

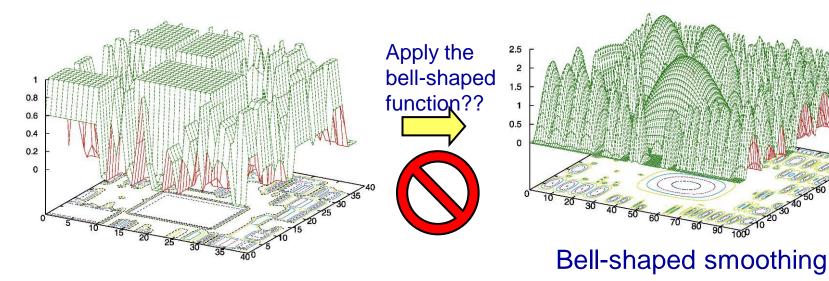
- (2) the density map is not smooth
- Some densities are too high to spread blocks over the mountains

Bell-Shaped Block Smoothing??

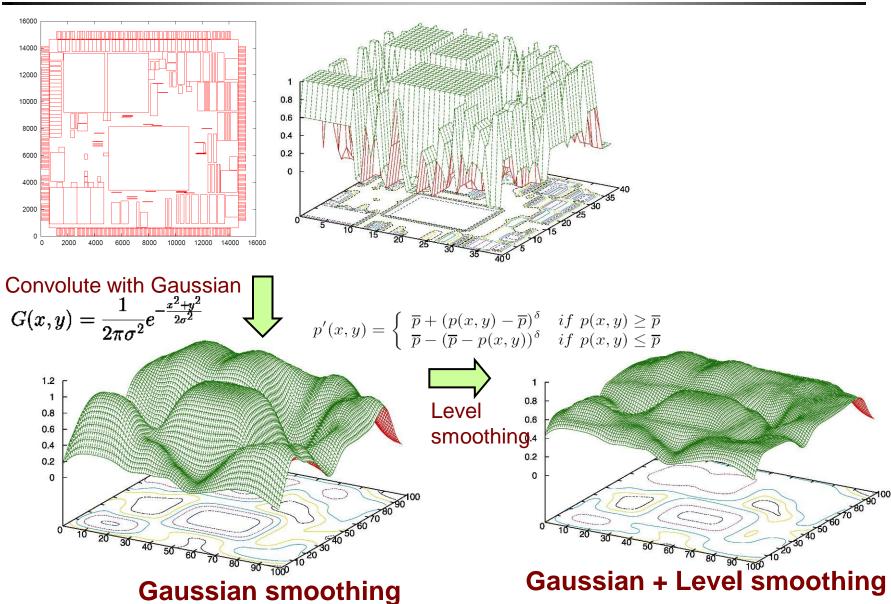


- (2) mountain heights are quite different
- there are many valleys among mountains
- might mis-guide the movement of blocks

[Kahng & Wang, ICCAD-04]

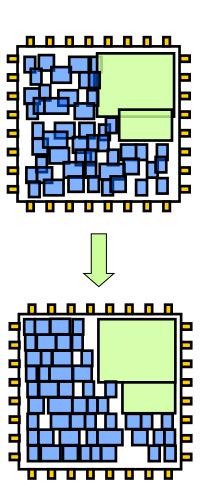


Preplaced Block Smoothing



Legalization

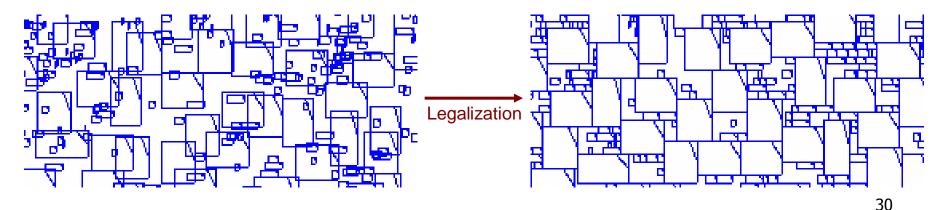
- Placement flow
 - Global placement
 - Legalization
 - Mixed-size legalization
 - Look-ahead legalization
 - Detailed placement

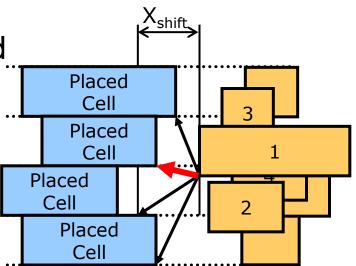


Mixed-Size Legalization

 Determine block legalization sequence by the x coordinate and block size

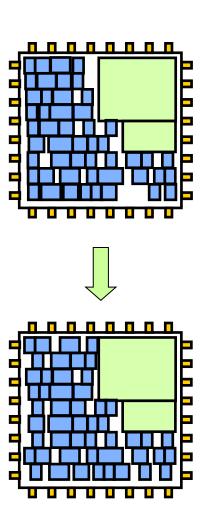
- Priority = $k_1 x_1 + k_2 w_1 + k_3 h_1$
 - x_i: x coordinate of block i
 - w_i(h_i): the width (height) of block i
- Larger blocks are legalized earlier
- Place block at the position with the smallest wirelength within a given range





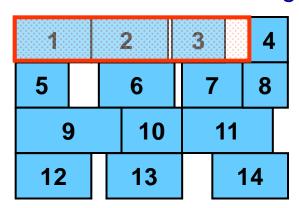
Detailed Placement

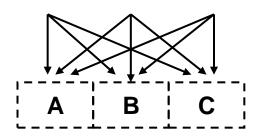
- Placement flow
 - Global placement
 - Legalization
 - Detailed placement
 - Cell matching for wirelength minimization
 - Cell sliding for density optimization



Cell Matching

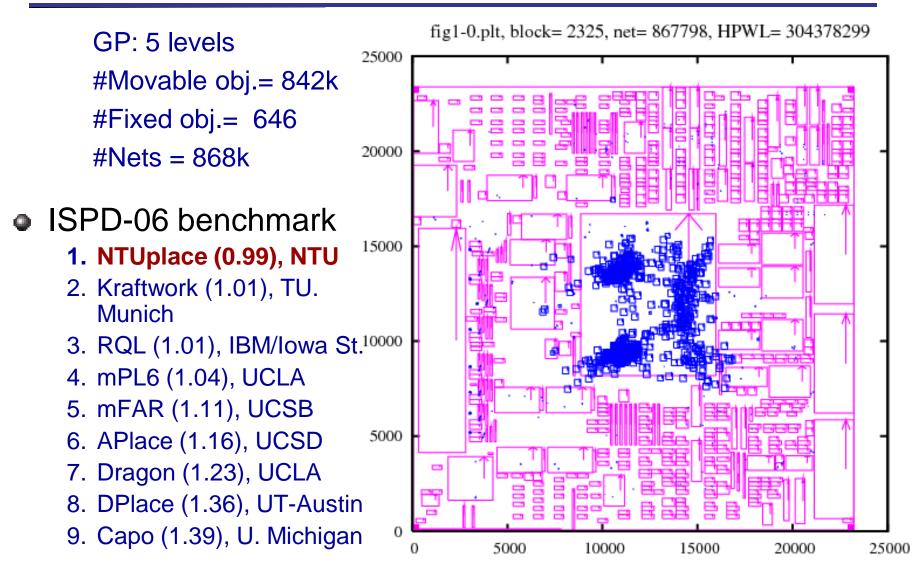
- For wirelength minimization
- Steps
 - 1. Select a window
 - Select blocks from the window
 - Create a bipartite matching problem (edge weight = wirelength)
 - 4. Find the minimum weighted matching to optimize the wirelength
 - 5. Update block positions
- Handle 200-300 cells at one time
 - Compared to branch-and-bound which can handle only 6 cells at one time due to its high time complexity





Assign cells {1,2,3} to locations {A,B,C}

Demo: NTUplace3 (circuit: adaptec5)



Demo: NTUplace3 (circuit: adaptec5)

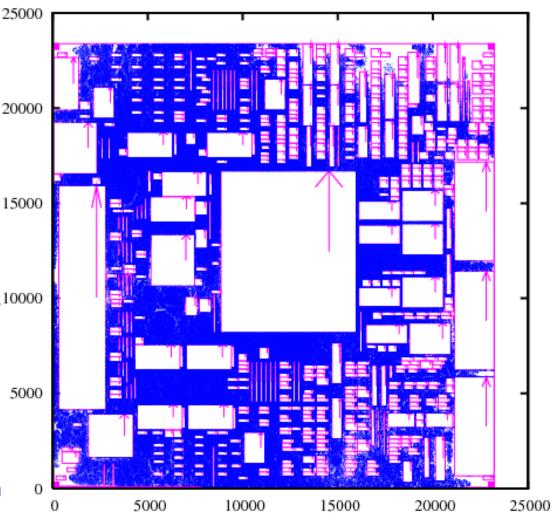
GP: 5 levels #Movable obj.= 842k #Fixed obj.= 646 #Nets = 868k

adaptec5.plt, block= 843224, net= 867798, HPWL= 387222315

25000 20000

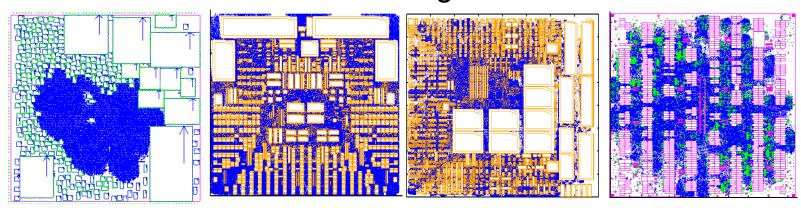
ISPD-06 benchmark

- 1. NTUplace (0.99), NTU
- 2. Kraftwork (1.01), TU. Munich
- 3. RQL (1.01), IBM/Iowa St.10000
- 4. mPL6 (1.04), UCLA
- 5. mFAR (1.11), UCSB
- 6. APlace (1.16), UCSD
- 7. Dragon (1.23), UCLA
- 8. DPlace (1.36), UT-Austin
- 9. Capo (1.39), U. Michigan



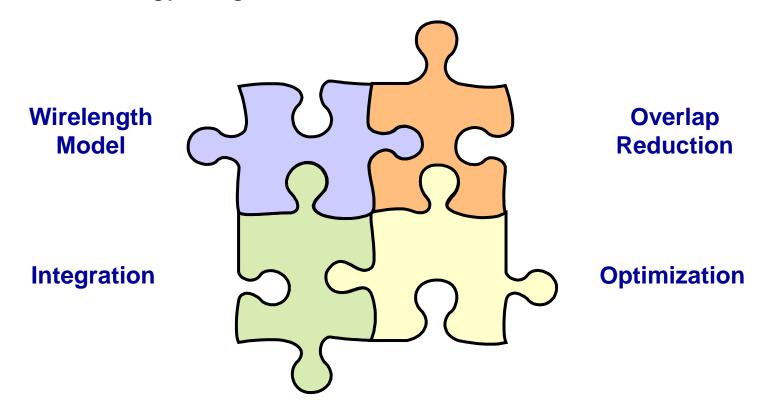
Placement Benchmarks

- Three state-of-the-art benchmark suites
 - ICCAD-04 IBM mixed-size (18 circuits): # Mov: 12K to 210K; Utilization: 80%
 - ISPD-05 placement contest (8 circuits): # Mov: 211K to 2.2M;# Fix: 543 to 23K; Utilization: 27% to 57%
 - ISPD-06 placement contest (8 circuits): # Mov: 330K to 2.5M;
 # Fix: 336 to 27K; Utilization: 26% to 71%; Target density: 50% to 90%
- NTUplace3 obtains best results for the three suites with both the WA and LSE wirelength models



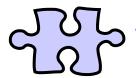
Essential Issues in Analytical Placement

 Chang, Jiang & Chen, "Essential issues in analytical placement algorithms," IPSJ Trans. System LSI Design Methodology, August 2009



Unit 5

NTUplace3 Example



Wirelength Model: Weighted-wirelenth (WA) or

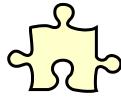
log-sum-exp (LSE) function



Overlap Reduction: Bell-shaped density model + Gaussian & Level smoothing



Integration: **Quadratic penalty method**



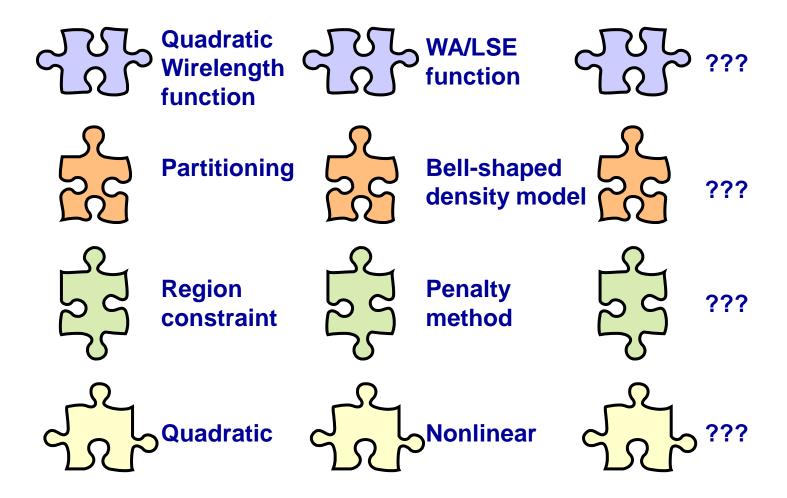
Nonlinear Optimization:

Modern Academic Analytical Placers

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	2	S	7
	8		

Placer	Wirelength Model	Overlap Reduction	Integration	Optimization	
APlace	LSE	Density	Penalty Method	Nonlinear	
BonnPlace	Quadratic	Partitioning	Region Constraint	Quadratic	
DPlace	Quadratic	Diffusion	Fixed Point	Quadratic	
FastPlace	Quadratic	Cell Shifting	Fixed Point	Quadratic	
FDP	Quadratic	Density	Fixed Point	Quadratic	
Gordian	Quadratic	Partitioning	Region Constraint	Quadratic	
hATP	Quadratic	Partitioning	Region Constraint	Quadratic	
Kraftwerk2	Bound2Bound	Density	Fixed Point	Quadratic	
mFAR	Quadratic	Density	Fixed Point	Quadratic	
mPL6	LSE	Density	Penalty Method	Nonlinear	
NTUplace3	LSE	Density	Penalty Method	Nonlinear	
RQL	Quadratic	Cell Shifting	Fixed Point	Quadratic	
Vassu	LSE	Assignment	Fixed Point	Nonlinear	

Other Combinations for New Placers?



3D IC Placement with TSVs

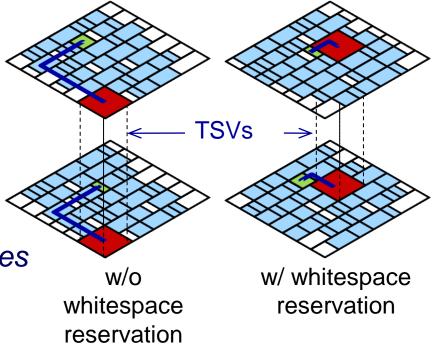
 Through-silicon vias (TSVs) cause significant challenges for 3D IC placement

TSVs

 Connect signals between device layers in a 3D IC

 Are usually placed at the whitespace among cells

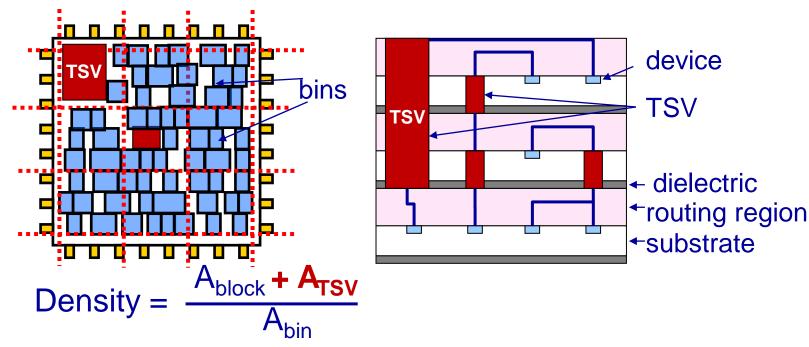
Affect the routing resources
 and increase the overall
 chip or package areas



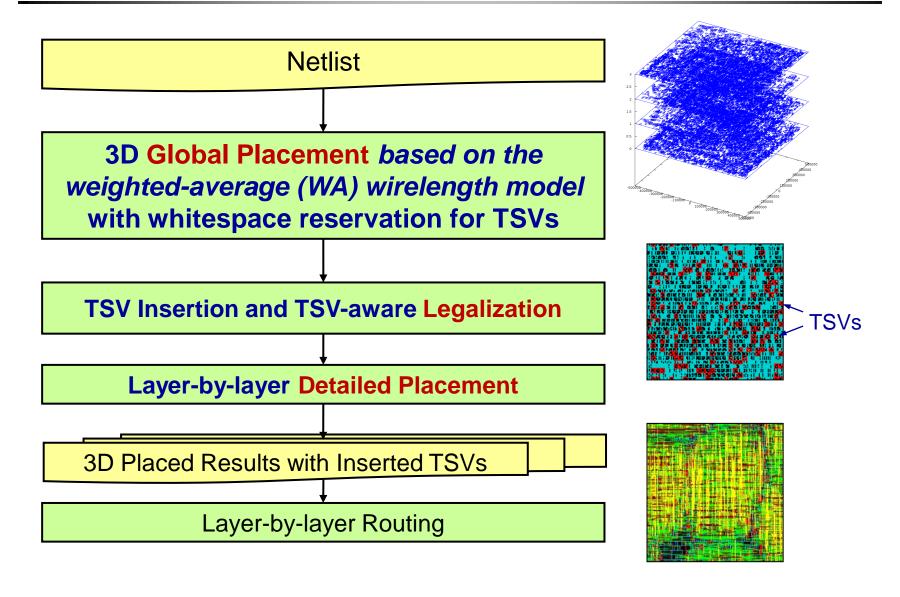
Need to reserve whitespace for TSV insertion

3D IC Placement Problem

- Given 3D IC layers and block dimensions, divide the placement region into bins
- Determine the layers and positions for all blocks min wirelength & TSV counts
 - s.t. 1. Density_b \leq MaximumDensity_b for each bin b
 - 2. No overlap between blocks



TSV-Aware 3D Analytical Placement Flow



3D Analytical Global Placement

Analytical formulation

min
$$\lambda_1 W(x,y) + \lambda_2 V(z)$$
 // minimize wirelength and TSV counts s.t. $(D_{b, k}(x,y,z) + T_{b, k}(x,y,z)) \le M_{b, k}$, $1 \le k \le K$

K: number of layers

 $D_{b,k}$: block density function for bin b on layer k

 $T_{b,k}$: TSV density for bin b on layer k

 $M_{b, k}$: max density for bin b on layer k

Relax the constraints into the objective function

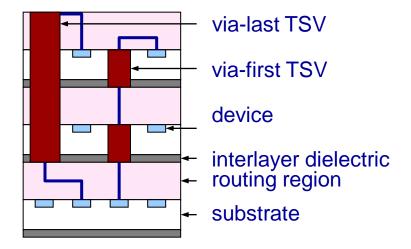
min
$$\lambda_1 W(x,y) + \lambda_2 V(z)$$

+ $\lambda_3 (\Sigma((D_{b,k}(x,y,z) + T_{b,k}(x,y,z)) - M_{b,k})^2)$

- Use the gradient method to solve it
- Increase λ_3 gradually to find the desired (x,y,z)

TSV Counts

- Two types of TSVs
 - Via-first TSVs interfere with device layer only
 - Via-last TSVs interfere with both device and metal layers



 For both types of TSVs, the number of TSVs used for each net can be defined as

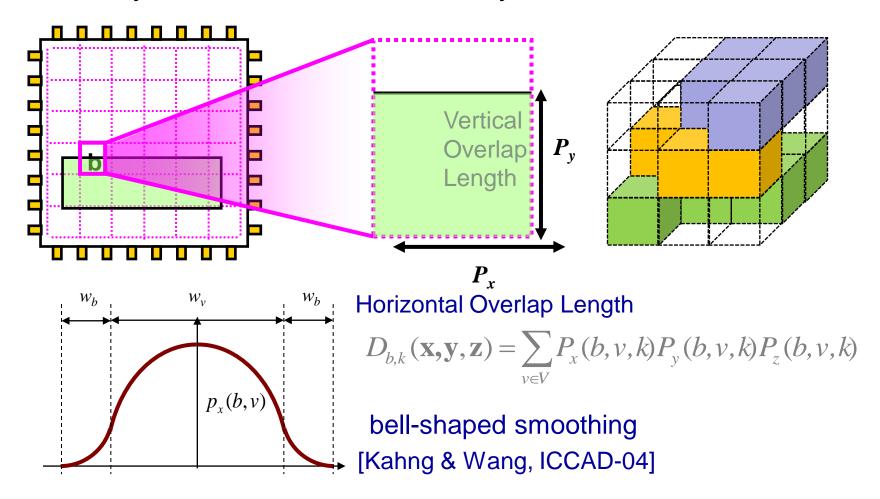
$$V(\mathbf{z}) = \sum_{e \in E} (\max_{v_i, v_j \in e} |z_i - z_j|)$$

WA approximation

$$V_{WA}(\mathbf{z}) = \sum_{e \in E} \left(\frac{\sum_{v_i \in e} z_i \exp(z_i / \gamma)}{\sum_{v_i \in e} \exp(z_i / \gamma)} - \frac{\sum_{v_i \in e} z_i \exp(-z_i / \gamma)}{\sum_{v_i \in e} \exp(-z_i / \gamma)} \right)$$

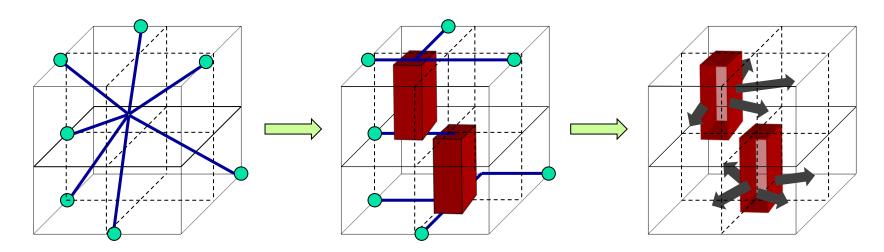
Cube Density Function

 Compute the block volume in each cube to obtain the density function for cube b on layer k



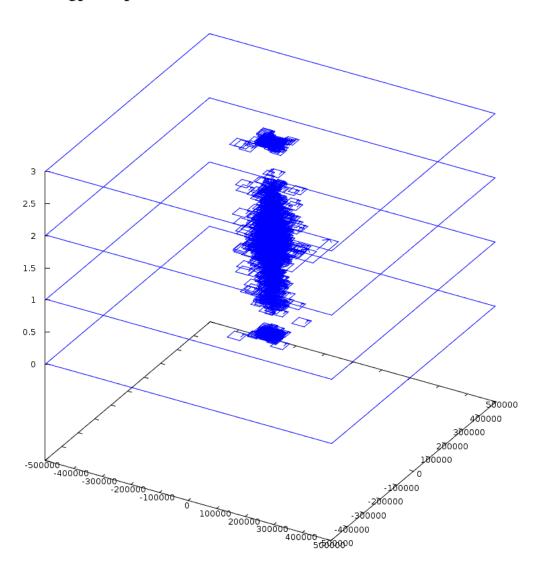
Whitespace Reservation for TSVs

- Reserve whitespace in the bounding cube of a net for TSVs
- $D_{b, k}(x, y, z) + T_{b, k}(x, y, z) \le M_{b, k}$
 - Block density D_{b, k}
 - TSV density $T_{b,k}$

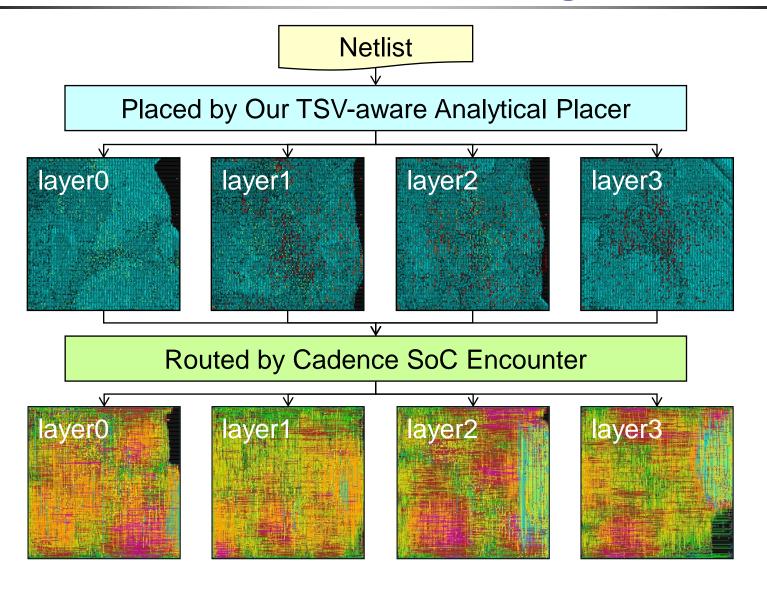


Demo: 3D Analytical Placement

aes_core.gp.1-1.plt, block= 4159, net= 20670, HPWL= 627177337



3D IC Placement and Routing Flow



3D IC Placement Comparisons

 Compared with [Cong & Luo, ASPDAC-09], our 3D placer can reduce the HPWL by 13% and TSV counts by 16%, with a 12X speedup

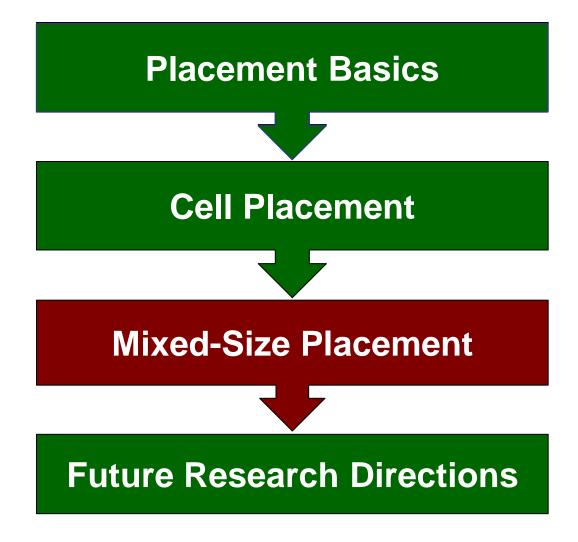
	HPWL	#TSV	Time
[Cong, ASPDAC-09]	1.00	1.00	1.00
Our placer	0.87	0.84	0.08

Compared with the state-of-the-art 3D placer [Kim et al., ICCAD-09], our placer achieves 10% shorter routed wirelength, 21% fewer TSV counts, and 18% smaller total silicon area, with a 2.6X speedup

	Routed Wirelength	#TSV	Silicon Area	Time
[Kim et al., ICCAD'09]	1.00	1.00	1.00	1.00
Our placer w/o WR	0.93	0.80	0.83	0.38
Our placer w/ WR	0.90	0.79	0.82	0.38

WR: whitespace reservation

Outline



Methods on Mixed-Size Placement

Type 1: Constructive approach

- Combine floorplanning and placement
- Examples: Capo, PATOMA, FLOP

Type 2: Two-stage approach

- Perform (1) macro placement and then (2) cell placement
- Examples: MP-tree, CG

Type 3: One-stage approach

- Place macro and cell simultaneously
- Examples: mPG-MS, APlace, mPL, UPlace, NTUplace3, etc.

Type 1: Constructive Approach

Type 1: Constructive approach

- Combine floorplanning and placement
- Examples: Capo, PATOMA, FLOP

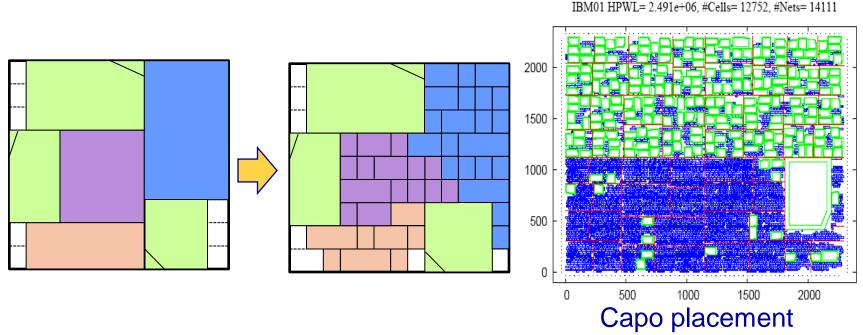
Type 2: Two-stage approach

- Perform (1) macro placement and then
 (2) cell placement
- Examples: MP-tree, CG

Type 3: One-stage approach

- Place macros and cells simultaneously
- Examples: mPG-MS, APlace, mPL, UPlace, NTUplace3, etc.

Type 1: Constructive Approach



- Combine floorplanning and placement
 - Capo [ICCAD'04], PATOMA [ASPDAC'05], FLOP [DAC'09]
 - Apply recursive min-cut bi-partitioning
- Keep macros overlap-free during placement
- The solution quality is often limited

Type 2: Two-Stage Approach

Type 1: Constructive approach

- Combine floorplanning and placement
- Examples: Capo, PATOMA, FLOP

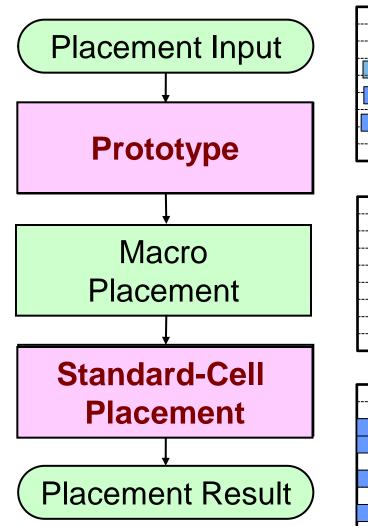
Type 2: Two-stage approach

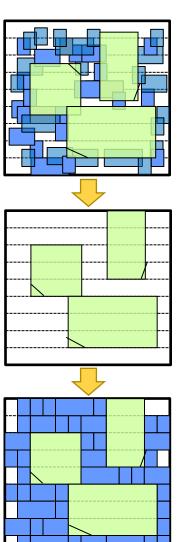
- Perform (1) macro placement and then (2) cell placement
- Examples: MP-tree, CG

Type 3: One-stage approach

- Place macros and cells simultaneously
- Examples: mPG-MS, APlace, mPL, UPlace, NTUplace3, etc.

Two-Stage Approach





wirelength optimization NTUplace3

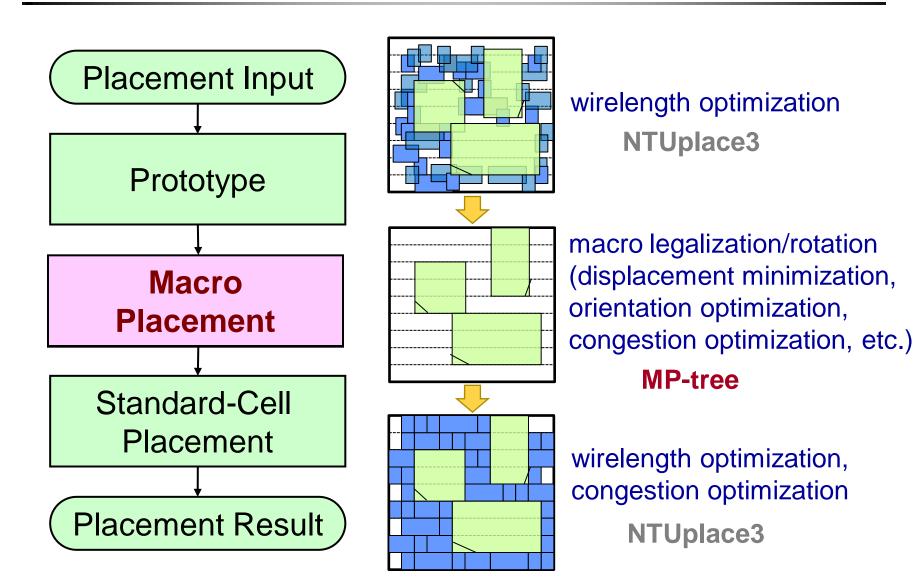
macro legalization/rotation (displacement minimization, orientation optimization, congestion optimization, etc.)

MP-tree

wirelength optimization, congestion optimization

NTUplace3

Two-Stage Approach



Macro Placement

Input

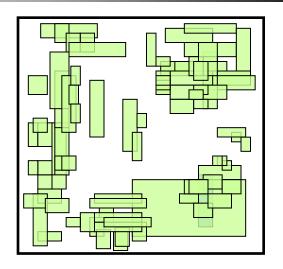
 An initial placement that considers both macros and standard cells and optimizes a simplified cost metric (e.g., wirelength)

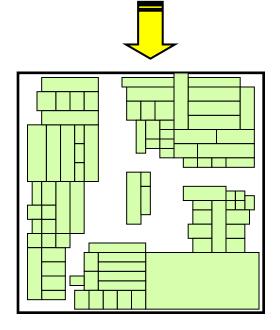
Objectives

- Remove all overlaps between macros
- Minimize macro movement (displacement)

Popular approaches

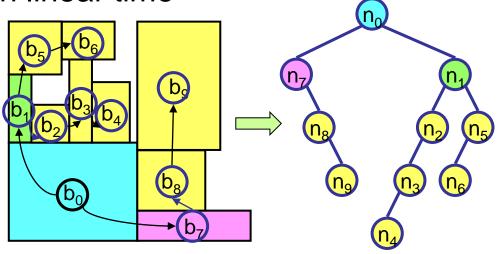
- Packing-based method: MP-tree [DAC'07, TCAD'08]
- Constraint graph-based method: CG [ICCAD'08]





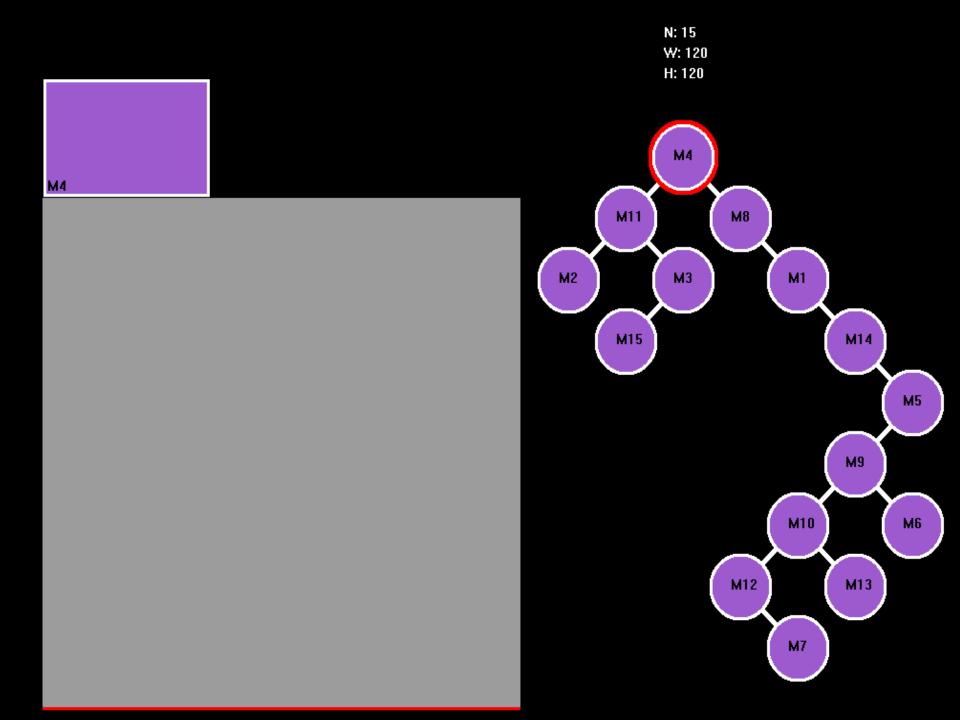
Macro Placement Using Multiple B*-Trees

- Construct an ordered binary tree (B*-tree)
 [Chang et al., DAC-2K]
 - Left child: the lowest, adjacent macro on the right $(x_i = x_i + w_i)$
 - Right child: the first macro above, with the same x-coordinate ($x_i = x_i$)
- Convert between a compacted placement and a B*-tree in linear time



Compact to left and bottom

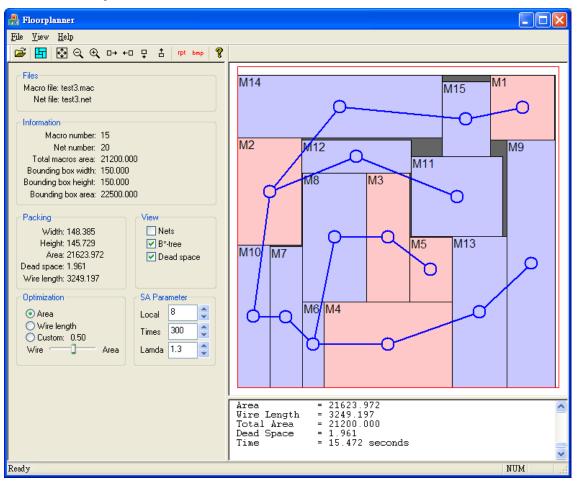
B*-tree



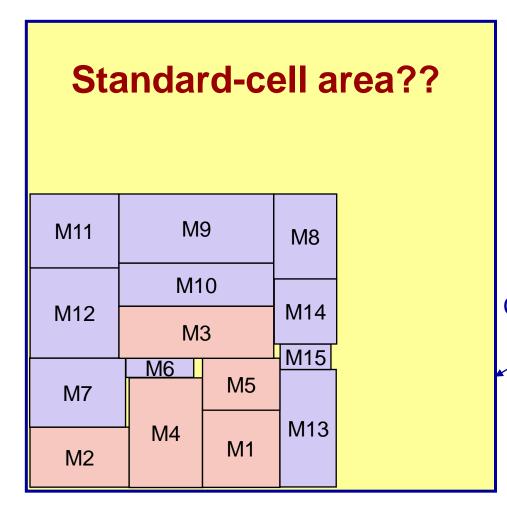
B*-tree Based Placer/Floorplanner

Rated the best representation for packing in [Chan, et. al, ISPD-05]

http://eda.ee.ntu.edu.tw/research.htm/



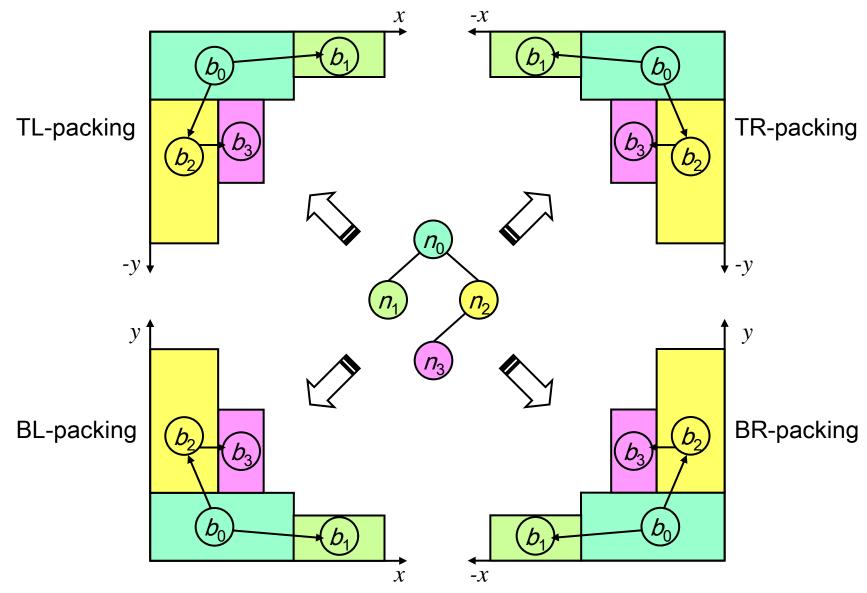
But What If %Macro Area Is Not High?



All macros will be packed together!!

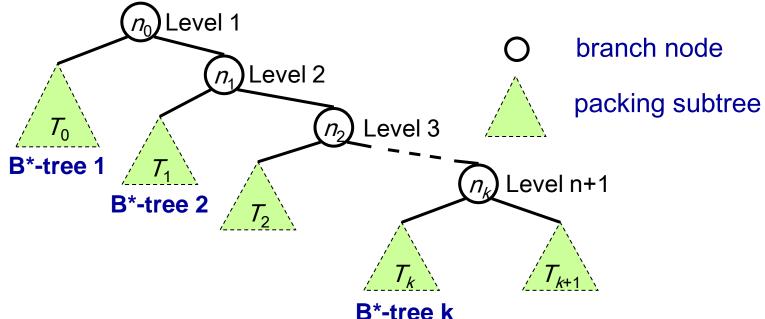
Chip outline

Multi-Packing (MP) Tree Representation



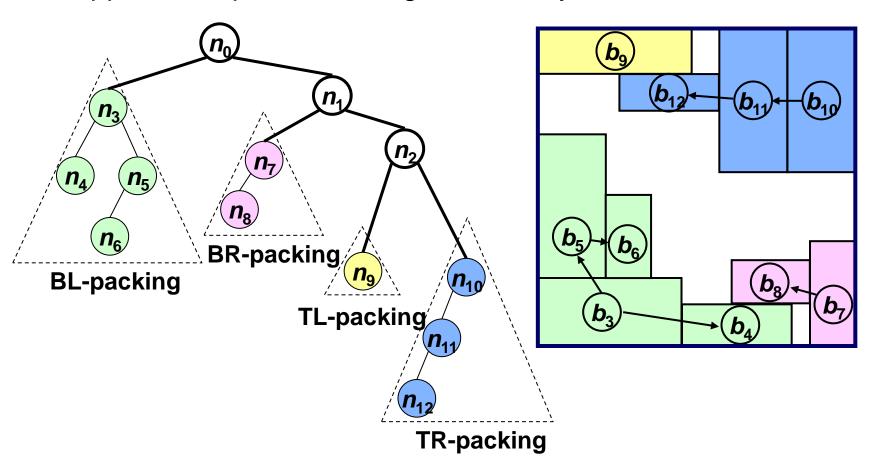
Generalized MP-Trees

- Working on four independent packing trees may not obtain a desired solution
 - Lack global interactions among different subproblems
- Key: Combine packing trees packing to different corners
 - Chen et al., "MP-trees: A packing-based macro placement algorithm for modern mixed-size designs," DAC'07 & TCAD'08
- Use the right skewed branch for easier implementation



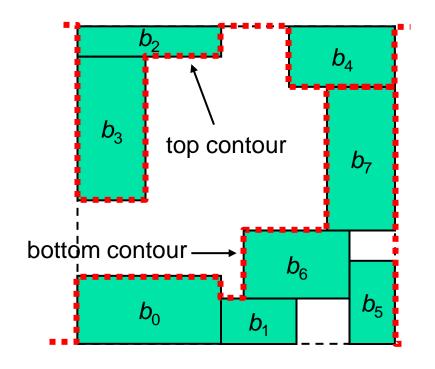
MP-tree Macro Placement Example

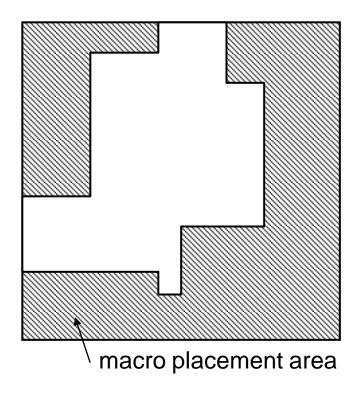
- Use four packing subtrees to handle a rectangular chip
- Applies to a placement region with any number of corners



Evaluation of a Macro Placement

- Macro placement area
- Wirelength
- Macro displacement





Demo: MP-Tree Placer (1/2)

Stage 1: Macro placement



Circuit: adaptec5

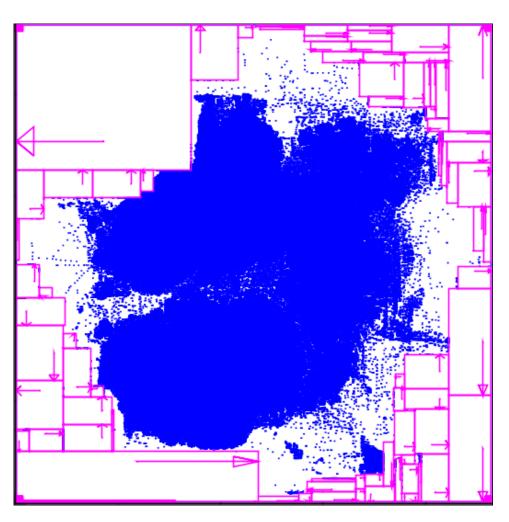
#Cell: 842k

#Net: 867k

#Macro: 76

Demo: MP-Tree Placer (2/2)

Stage 2: Standard-cell placement



Circuit: adaptec5

#Cell: 842k

#Net: 867k

#Macro: 76

HPWL: 3.27e6

Results on the ISPD-06 Benchmarks

 The higher the chip utilization rate, the more the wirelength reduction.

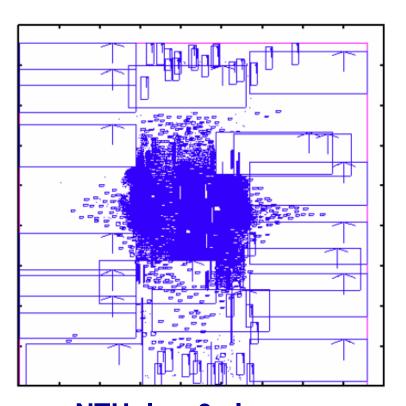
	NTUplace3 HPWL (e7)							
Circuit	85% util		90%	util	95% util			
	w/o	w/ MPT	w/o	w/ MPT	w/o	w/ MPT		
adaptec5	30.55	30.40	30.29	30.48	47.25	32.30		
newblue1	6.64	6.30	6.74	6.38	6.85	6.62		
newblue2	20.44	21.23	20.96	19.29	25.34	20.61		
newblue3	NR	31.21	NR	29.64	NR	38.68		
newblue4	22.82	21.41	26.70	22.68	26.83	23.77		
newblue5	41.09	40.21	49.12	47.97	72.56	68.14		
newblue6	45.45	45.46	53.14	47.60	66.51	65.21		
newblue7	111.92	114.12	NR	120.15	NR	136.87		
Average	1.00	0.99	1.00	0.93	1.00	0.88		

*w/o: NTUplace3 alone

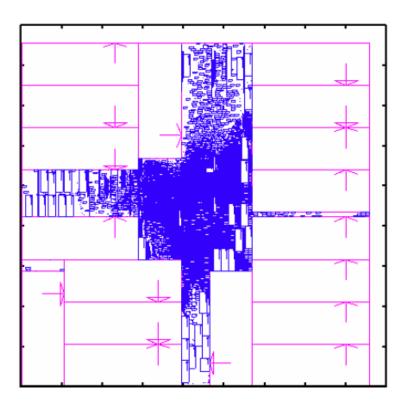
*w/ MPT: MP-tree + NTUplace3

NR: no legal result

ISPD-06 newblue3 Layouts



NTUplace3 alone (failed to find a legal placement)



MP-tree + NTUplace3

Integration with Other Placers

- Capo 10.2: 12% wire reduction, 21% more CPU time
- mPL6: 4% wire reduction, more robust

	Capo 10.2				mPL6			
Circuit	HPWL (e7)		CPU (min)		HPWL (e7)		CPU (min)	
	w/o	MPT	w/o	MPT	w/o	MPT	w/o	MPT
adaptec5	38.29	33.52	432	537	NR	28.72	NR	138
newblue1	9.56	6.71	155	109	6.45	6.18	47	47
newblue2	25.99	22.05	287	234	NR	18.18	NR	94
newblue3	33.27	34.00	263	432	NR	31.11	NR	116
newblue4	26.93	24.00	311	451	NR	21.04	NR	93
newblue5	47.07	42.96	775	894	NR	39.94	NR	239
newblue6	55.22	49.23	795	882	NR	45.33	NR	296
newblue7	119.48	107.99	1795	2752	NR	94.76	NR	588
Average	1.00	0.88	1.00	1.21	1.00	0.96	1.00	0.99

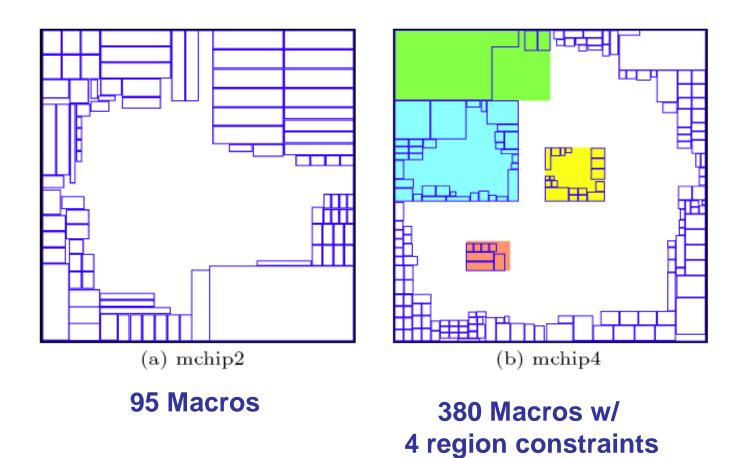
Nat'l Taipei Univ.-2008

Mchip Benchmark Results

- Cell ~1320K, macro ~380, macro area ratio ~66%
- Placed HPWL is 35% shorter than Capo's
- Routed WL is 55% shorter than Capo's
- Compared with two leading commercial placers
 - 6% -- 56% shorter placed HPWL
 - 7% -- 67% shorter routed WL

Mohin	HPWL		Route	ed WL	GRC Overflow	
Mchip	Ours	Capo	Ours	Capo	Ours	Capo
Mchip1	5.26	5.84	6.13	6.56	0.7%	0.7%
Mchip2	4.72	5.65	5.34	6.65	0.1%	1.0%
Mchip3	5.26	10.00	6.02	16.90	0.1%	36.4%
Mchip4	11.76	14.12	13.27	14.16	0.1%	1.4%
Mchip5	8.92	NA	9.85	NA	0.0%	NA
Avg	1.00	1.35	1.00	1.55		

Mchip Benchmark Results



Type 3: One-stage Approach

Type 1: Constructive Approach

- Combine floorplanning and placement
- Examples: Capo, PATOMA, FLOP

Type 2: Two-stage Approach

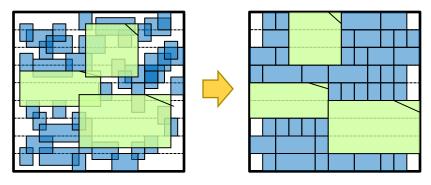
- Perform (1) macro placement and then
 (2) cell placement
- Examples: MP-tree, CG

Type 3: One-stage Approach

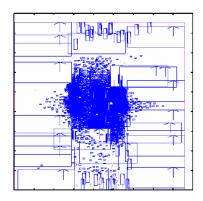
- Place macros and cells simultaneously
- Examples: mPG-MS, APlace, mPL, UPlace, NTUplace3, etc.

One-Stage Approach

- One-stage mixed-size placers
 - Place both macros and cells simultaneously
 - mPG-MS [ASPDAC'03], APlace [ICCAD'04], mPL [ISPD'05], UPlace [ISPD'05], NTUplace3 [ICCAD'06, TCAD'08], etc.



- Analytical placement
 - Has been shown to be most effective for cell placement
 - Key limitation: macro handling in global placement
 - Macro rotation and legalization



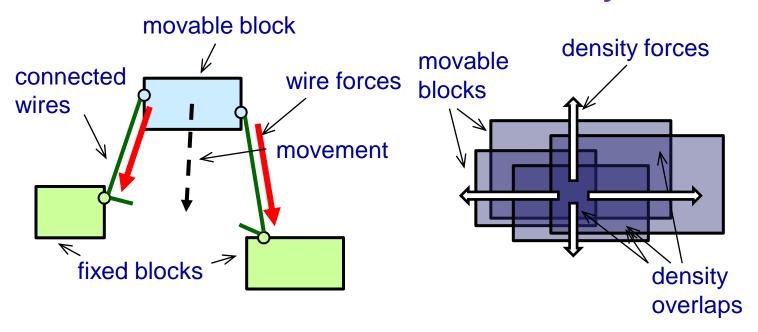
Forces in Analytical Formulation

Analytical placement formulation

min
$$W(x, y) + \lambda \Sigma (D_b(x, y) - M_b)^2$$

Wire force

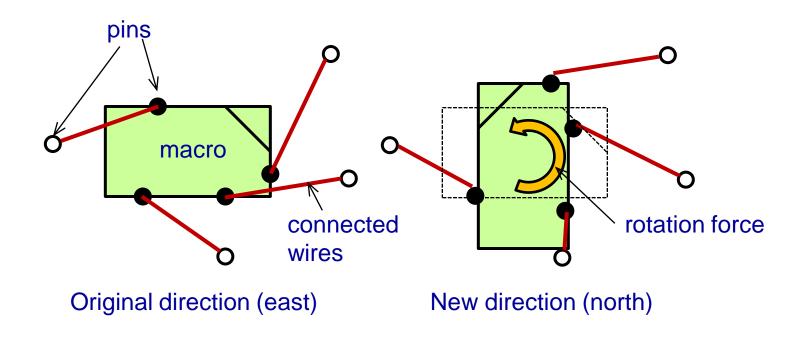
Density force



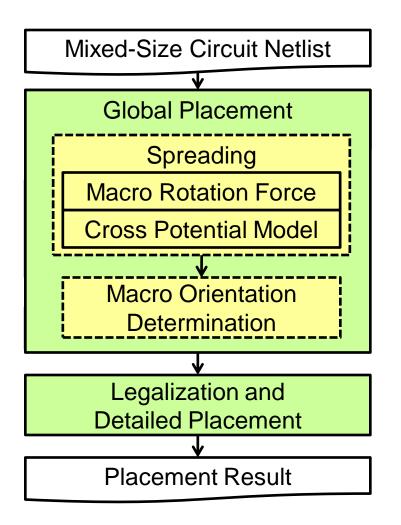
Rotation?

First Unified Approach

- Hsu & Chang [ICCAD'10] present the first attempt to rotate and legalize macros during analytical placement
- Macro rotation force
 - Is induced from wire connections, similar to wirelength gradient (wire force) for wirelength optimization



Unified Analytical Placement: NTUplace-m

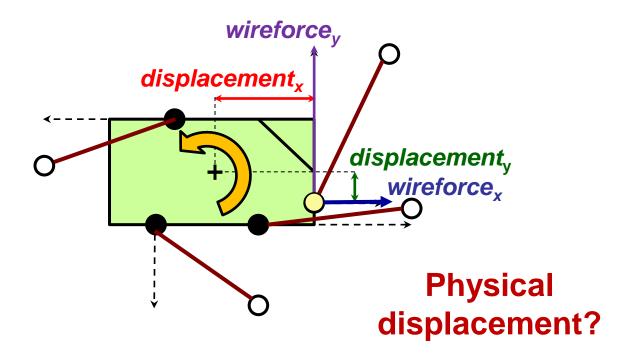


Global placement is the most critical step in placement

Rotation Force Modeling: Torque

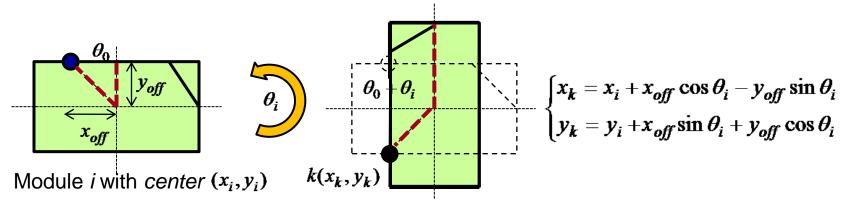
- Model the rotation force according to wire forces
 - Use the *torque* concept in physics to determine the orientations of macros

 $Torque = wireforce_x \times displacement_y + wireforce_y \times displacement_x$



Macro Rotation Force Modeling

• New (x_k, y_k) from (x_i, y_i) after rotation by degree θ_i



Rotation force: gradient of wirelength on the direction of the rotation degree => differentiate wirelength function by degree θ_i virtual displacements

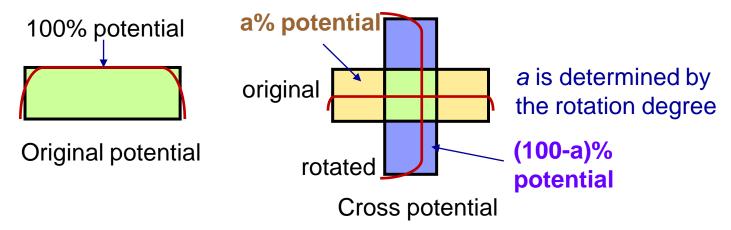
$$\frac{\partial W}{\partial \theta_i} = \frac{\partial W}{\partial x_k} \cdot \frac{\partial x_k}{\partial \theta_i} + \frac{\partial W}{\partial y_k} \cdot \frac{\partial y_k}{\partial \theta_i} = \frac{\partial W}{\partial x_k} \cdot (-x_{off} \sin \theta_i - y_{off} \cos \theta_i) + \frac{\partial W}{\partial y_k} \cdot (x_{off} \cos \theta_i - y_{off} \sin \theta_i)$$

wire forces on x and y directions at pin k

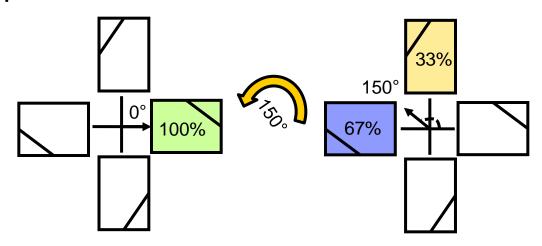
- Continuous degree? But macro rotation is non-continuous!!
 - Cross potential model

Cross Potential Model

Consider both the original and rotated potentials

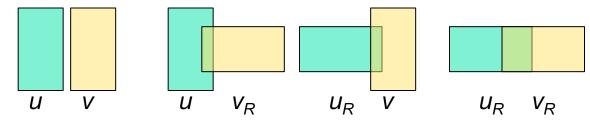


Example



Macro Orientation Determination

- At the end of global placement, each macro is rotated to the direction with max potential and min overlaps
- Objective: minimize overlaps among macros
 - For macros u and v, there are \leq 4 overlapping combinations



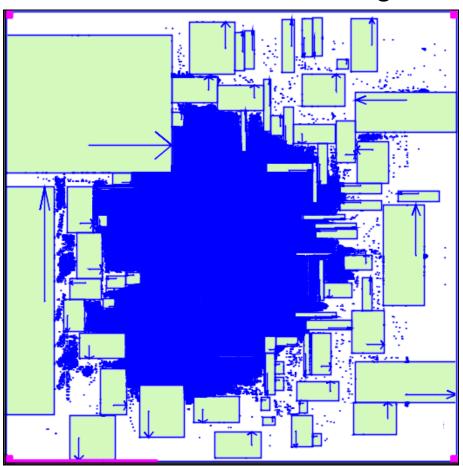
Overlap function for two macros u and v

$$\Psi(u, v) = (1-r_u)(1-r_v)\varphi(u, v) + (1-r_u)r_v\varphi(u, v_R) + r_u(1-r_v)\varphi(u_R, v) + r_ur_v\varphi(u_R, v_R)$$

- $u_R(v_R)$: rotated macro of u(v)
- $\varphi(u,v)$: overlaps between two macros with given orientations
- $r_u = 0$, macro u rotated by 0 (or 180) degree $r_u = 1$, macro u rotated by 90 (or 270) degree
- Can use ILP to solve this problem

Demo: Unified Mixed-Size Placement

- Simultaneous macro and standard-cell placement with macro orientation handling
- At least 5% better wirelength than existing placers



Circuit: adaptec5

#Cell: 842k

#Net: 867k

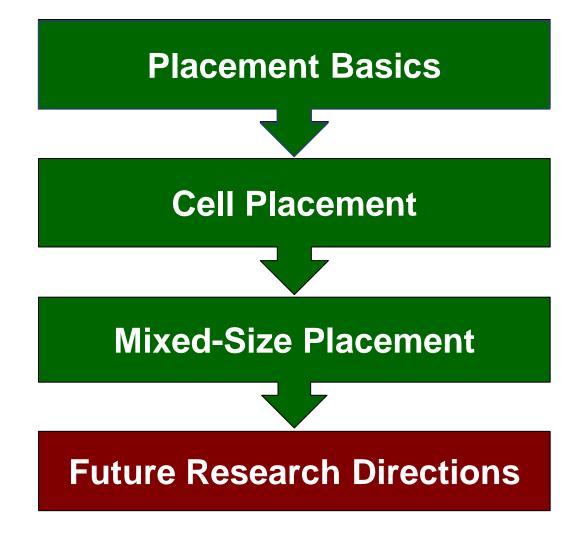
#Macro: 76

HPWL: 2.86e8

Comparisons

Mixed-size placement	Pros	Cons
Constructive approach	 Keep macros overlap-free with floorplanning Is fast with good scalability 	 Solution quality is usually limited by the intrinsic problems with partitioning Is less effective for spare designs
Two-stage approach	 Is robust in finding legal placement Is widely used in the industry Is suitable for dense design with higher utilizations 	 Need a good macro placer Gaps between placements of macros and standard cells limit the quality of the final placements
One-stage approach	 Analytical placement is most effective for standard-cell placement Close the gap between macro and cell placement Can handle sparse designs well 	Special consideration for macro handling, macro legalization and rotation, are needed

Outline

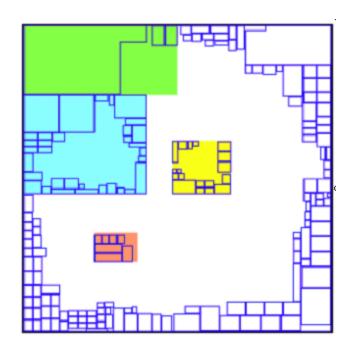


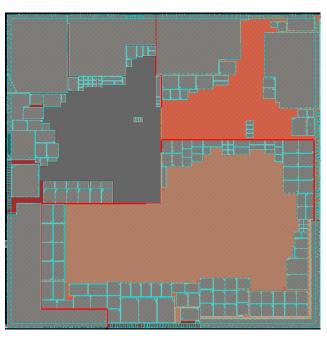
Future Research Directions

- Large-scale mixed-size placement
- Routability-driven placement
- Timing-driven placement
- Power-delivery-aware placement
- Simultaneous clock network synthesis and placement
- Manufacturability-aware placement
- Stress-aware placement
- Thermal-aware 3D IC placement

Large-Scale Mixed-Size Placement

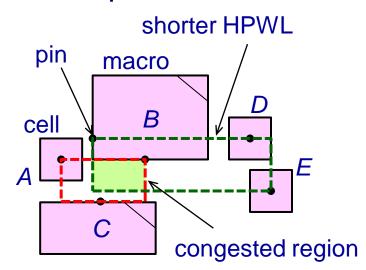
- We still have a long way to go for large-scale mixed-size placement!!
 - Find best trade-offs among existing approaches?
 - Need to consider many other placement constraints
 - Could be multiple mixed-size domains: recursive MP-trees?



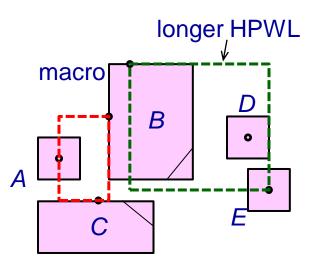


Routability-Driven Placement

- Routability issues for mixed-size placement becomes more challenging: ISPD 2011 Contest Problem!
 - Macro porosity, ratio of available routing resources above a macro block, and macro rotation induce more problems



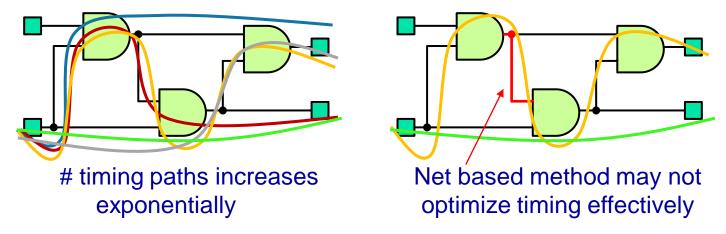
Wirelength minimization Routing congested region occurs



Congestion optimization
Macro B is rotated

Timing-Driven Placement

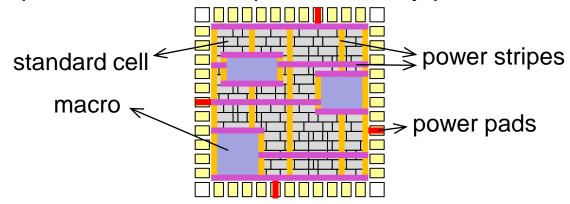
- Two major techniques for timing-driven placement
 - Path-based methods incur prohibitively time complexity due to the exponentially increasing number of paths
 - Net-based methods lack the global view of the full path



- A timing optimization technique with low-complexity and high controllability is desired
- Timing-driven placement with macro awareness
 - Macros cause wirelength and routability issues
 - Timing requirements for macro blocks should be considered

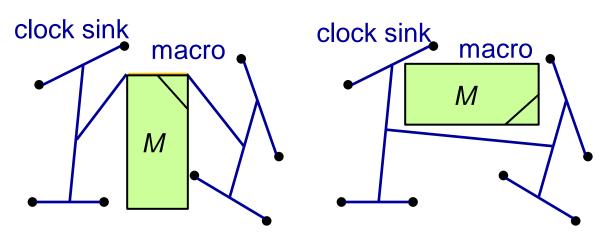
Power-Delivery-Aware Placement

- Voltage (IR) drops
 - Limit circuit performance, slow down the slew rate, and increase power consumption
 - Depend on the distance between placed macros/cells and power network
 - Should be considered during placement to reduce the power consumption
- For mixed-size designs, big macros introduce additional power rings and power stripes
 - Make power network and power delivery problems more difficult



Clock-Network-Aware Placement

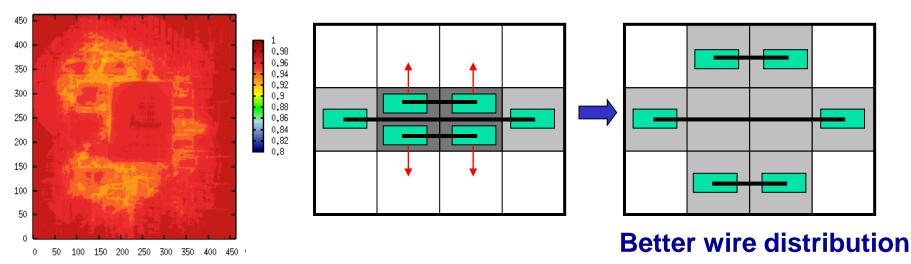
- Clock network synthesis (CNS) constructs the clock network which distributes clock signals from a source point to all the sequential elements connected it
- For modern mixed-size designs, big macros might cause obstacles for clock network synthesis



CNS designs with different macro orientations and positions

Manufacturability-Aware Placement

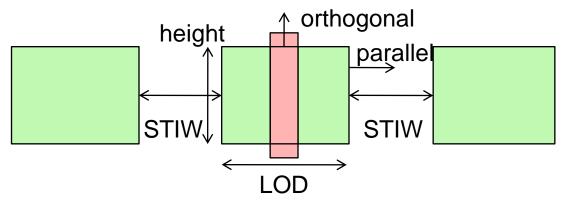
- Predictive Chemical Mechanical Polishing (CMP) model
 - The number of dummy fills and normalized copper thickness are functions of wire density [Cho et al, ICCAD-06]
- Wire density optimization is limited by pin locations
- Shall move cells/pins out of the high wire-density regions during placement
 - Chen, et al., ISPD-08 (TCAD, 2008)



Normalized Copper Thickness Map

Stress-Aware Placement

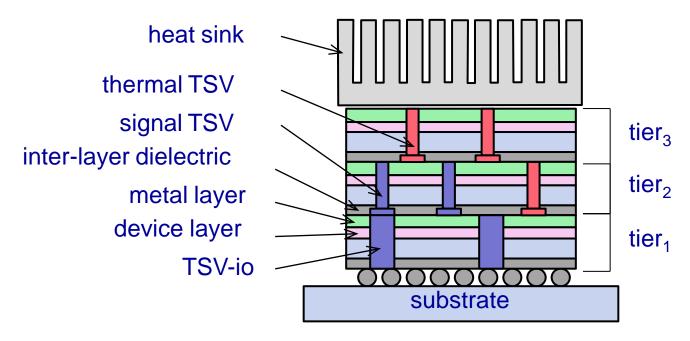
- Shallow trench isolation (STI) is the mainstream CMOS isolation technique for advanced circuit design
 - By exploiting STI wells between device active regions, STI stress can effectively improve transistor performance
 - STI width (STIW) and length of diffusion (LOD)



- MOB_{L,R} = γ[(LOD/2)^α + β/STIW_{L,R}] [Kahng et al., ICCAD'07]
 - If STIW↑ or LOD↓, then pMOS mobility ↑
 - If STIW↓ or LOD↑, then nMOS mobility ↑
- Problem: place cells to optimize STIW between neighboring cells while achieving timing requirements

Thermal-aware 3D IC Placement

- Problem: Place cells into multiple tiers (dies) to optimize wirelength, etc.
- Important issues: reliability, thermal, routability, mixedsize design, etc



Conclusions

Cell placement

- NTUplace3 analytical placement framework
- The WA wirelenth model for analytical global placement

Mixed-size placement designs

- Become a mainstream for modern circuit designs
- Incur more challenges to modern circuit placement

Major mixed-size placement approaches

- Two-stage approach: place macros followed by standard cells
- One-stage approach: handling macro rotation & orientation is key
- Each has its pros and cons: trade-offs among solution quality, runtime efficiency, and utilization flexibility

Many modern challenges, e.g.,

Multiple domains/objectives/constraints: routability, timing, power,
 CTS, stress, 3D IC designs, etc.

Keys to Our Research Solutions: CAR



Criticality



Abstraction



Restriction

